

# STB15NM60N - STF/I15NM60N STP15NM60N - STW15NM60N

N-channel 600V - 0.270Ω - 14A - D<sup>2</sup>/I<sup>2</sup>PAK - TO-220/FP - TO-247  
Second generation MDmesh™ Power MOSFET

## Features

Type	V <sub>DSS</sub> (@T <sub>jmax</sub> )	R <sub>DS(on)</sub>	I <sub>D</sub>
STB15NM60N	650V	< 0.299Ω	14A
STI15NM60N	650V	< 0.299Ω	14A
STF15NM60N	650V	< 0.299Ω	14A <sup>(1)</sup>
STP15NM60N	650V	< 0.299Ω	14A
STW15NM60N	650V	< 0.299Ω	14A

1. Limited only by maximum temperature allowed

- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance

## Description

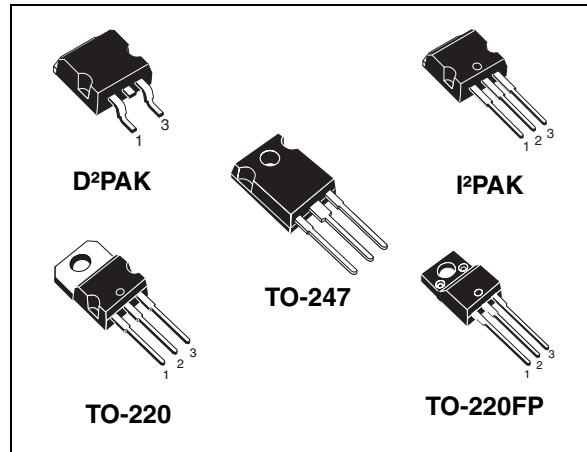
This series of devices implements the second generation of MDmesh™ Technology. This revolutionary Power MOSFET associates a new vertical structure to the Company's strip layout to yield one of the world's lowest on-resistance and gate charge. It is therefore suitable for the most demanding high efficiency converters

## Application

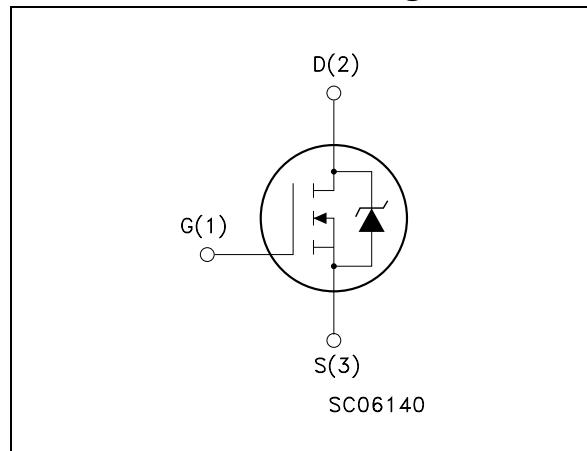
- Switching applications

## Order codes

Part number	Marking	Package	Packaging
STB15NM60N	B15NM60N	D <sup>2</sup> PAK	Tape & reel
STI15NM60N	I15NM60N	I <sup>2</sup> PAK	Tube
STF15NM60N	F15NM60N	TO-220FP	Tube
STP15NM60N	P15NM60N	TO-220	Tube
STW15NM60N	W15NM60N	TO-247	Tube



## Internal schematic diagram



# 1 Electrical ratings

**Table 1. Absolute maximum ratings**

Symbol	Parameter	Value		Unit
		D <sup>2</sup> PAK/I <sup>2</sup> PAK TO-220/TO-247	TO-220FP	
V <sub>DS</sub>	Drain-source voltage ( $V_{GS}=0$ )	600		V
V <sub>GS</sub>	Gate-source voltage	± 25		V
I <sub>D</sub>	Drain current (continuous) at $T_C = 25^\circ\text{C}$	14	14 <sup>(1)</sup>	A
I <sub>D</sub>	Drain current (continuous) at $T_C = 100^\circ\text{C}$	9	9 <sup>(1)</sup>	A
I <sub>DM</sub> <sup>(2)</sup>	Drain current (pulsed)	56	56 <sup>(1)</sup>	A
P <sub>TOT</sub>	Total dissipation at $T_C = 25^\circ\text{C}$	125	30	W
dv/dt <sup>(3)</sup>	Peak diode recovery voltage slope	15		V/ns
V <sub>ISO</sub>	Insulation withstand voltage (RMS) from all three leads to external heat sink ( $t=1\text{s}; T_C=25^\circ\text{C}$ )	--	2500	V
T <sub>j</sub> T <sub>stg</sub>	Operating junction temperature Storage temperature	-55 to 150		°C

1. Limited only by maximum temperature allowed
2. Pulse width limited by safe operating area
3.  $I_{SD} \leq 14\text{A}$ ,  $di/dt \leq 400\text{A}/\mu\text{s}$ ,  $V_{DD} = 80\%$   $V_{(BR)DSS}$

**Table 2. Thermal data**

Symbol	Parameter	D <sup>2</sup> PAK/I <sup>2</sup> PAK TO-220/TO-247	TO-220FP	Unit
R <sub>thj-case</sub>	Thermal resistance junction-case max	1	4.2	°C/W
R <sub>thj-amb</sub>	Thermal resistance junction-amb max	62.5		°C/W
T <sub>I</sub>	Maximum lead temperature for soldering purposes	300		°C

**Table 3. Avalanche characteristics**

Symbol	Parameter	Max value	Unit
I <sub>AS</sub>	Avalanche current, repetitive or not-repetitive (pulse width limited by T <sub>j</sub> max)	6	A
E <sub>AS</sub>	Single pulse avalanche energy (starting T <sub>j</sub> =25°C, I <sub>D</sub> =I <sub>AS</sub> , V <sub>DD</sub> = 50V)	300	mJ

## 2 Electrical characteristics

( $T_{CASE}=25^\circ\text{C}$  unless otherwise specified)

**Table 4. On/off states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$I_D = 1\text{mA}$ , $V_{GS} = 0$	600			V
$dv/dt^{(1)}$	Drain-source voltage slope	$V_{DD} = 480\text{V}$ , $I_D = 14\text{A}$ , $V_{GS} = 10\text{V}$		30		V/ns
$I_{DSS}$	Zero gate voltage drain current ( $V_{GS} = 0$ )	$V_{DS} = \text{Max rating}$ , $V_{DS} = \text{Max rating, } @ 125^\circ\text{C}$			1 100	$\mu\text{A}$ $\mu\text{A}$
$I_{GSS}$	Gate body leakage current ( $V_{DS} = 0$ )	$V_{GS} = \pm 20\text{V}$			100	nA
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}$ , $I_D = 250\mu\text{A}$	2	3	4	V
$R_{DS(\text{on})}$	Static drain-source on resistance	$V_{GS} = 10\text{V}$ , $I_D = 7\text{A}$		0.270	0.299	$\Omega$

1. Value measured at turn off under inductive load

**Table 5. Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$g_{fs}^{(1)}$	Forward transconductance	$V_{DS} = 15\text{V}$ , $I_D = 7\text{A}$		10		S
$C_{iss}$ $C_{oss}$ $C_{rss}$	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 50\text{V}$ , $f = 1\text{MHz}$ , $V_{GS} = 0$		1250 100 10		pF pF pF
$C_{oss \text{ eq.}}^{(2)}$	Equivalent output capacitance	$V_{GS} = 0$ , $V_{DS} = 0\text{V}$ to $480\text{V}$		137		pF
$R_g$	Gate input resistance	$f=1\text{MHz}$ Gate DC Bias=0 Test signal level=20mV open drain		6.0		$\Omega$
$Q_g$ $Q_{gs}$ $Q_{gd}$	Total gate charge Gate-source charge Gate-drain charge	$V_{DD} = 480\text{V}$ , $I_D = 14\text{A}$ $V_{GS} = 10\text{V}$		37 6 18		nC nC nC

1. Pulsed: pulse duration =  $300\mu\text{s}$ , duty cycle 1.5%

2.  $C_{oss \text{ eq.}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$

**Table 6. Switching times**

<b>Symbol</b>	<b>Parameter</b>	<b>Test conditions</b>	<b>Min</b>	<b>Typ</b>	<b>Max</b>	<b>Unit</b>
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 300V, I_D = 7A,$ $R_G = 4.7\Omega, V_{GS} = 10V$	12 14 80 30	ns ns ns ns	ns ns ns ns	ns ns ns ns
$t_r$	Rise time					
$t_{d(off)}$	Turn-off delay time					
$t_f$	Fall time					

**Table 7. Source drain diode**

<b>Symbol</b>	<b>Parameter</b>	<b>Test conditions</b>	<b>Min</b>	<b>Typ</b>	<b>Max</b>	<b>Unit</b>				
$I_{SD}$	Source-drain current		14 56	A A	14 56	A A				
$I_{SDM}^{(1)}$	Source-drain current (pulsed)									
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 14A, V_{GS}=0$	390 5 25	ns $\mu C$ A	1.3	V				
$t_{rr}$	Reverse recovery time	$I_{SD} = 14A, di/dt = 100A/\mu s,$ $V_{DD} = 100V, T_j = 25^\circ C$								
$Q_{rr}$	Reverse recovery charge									
$I_{RRM}$	Reverse recovery current									
$t_{rr}$	Reverse recovery time	$V_{DD} = 100V$ $di/dt = 100A/\mu s, I_{SD} = 14A$ $T_j = 150^\circ C$	500 7 25	ns $\mu C$ A	ns $\mu C$ A	ns $\mu C$ A				
$Q_{rr}$	Reverse recovery charge									
$I_{RRM}$	Reverse recovery current									

1. Pulse width limited by safe operating area
2. Pulsed: pulse duration = 300 $\mu$ s, duty cycle 1.5%